

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICESUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT
(Use several sheets if necessary)ATTY. DOCKET NO.
671096.403USPCAPPLICATION NO.
10/518,651APPLICANTS
Andrei NIKULINFILING DATE
July 18, 2005GROUP ART UNIT
2882

U.S. PATENT DOCUMENTS

| *EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
|----------------------|----|-----------------|------|------|-------|----------|-------------------------------|
| | AA | | | | | | |
| | AB | | | | | | |
| | AC | | | | | | |
| | AD | | | | | | |
| | AE | | | | | | |
| | AF | | | | | | |
| | AG | | | | | | |
| | AH | | | | | | |

FOREIGN PATENT DOCUMENTS

| | | DOCUMENT NUMBER | DATE | COUNTRY | TRANSLATION | |
|--|----|--------------------|------|---------|-------------|----|
| | | | | | YES | NO |
| | AI | | | | | |
| | AJ | | | | | |
| | AK | | | | | |
| | AL | | | | | |
| | AM | | | | | |

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

| | | |
|----|----|-----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| CT | AN | Siu, Karen, et al., "X-ray phase retrieval in high-resolution refraction data from amorphous materials," <i>Applied Physics Letters</i> , 79(13):2112-2114, September 24, 2001. |
| ↓ | AO | Siu, Karen, et al., "Phase Retrieval X-ray Diffractometry (PRXRD): Refraction/Small angle scattering data applications," <i>Proc. SPIE, Advances in X-Ray Optics</i> , 4145: 157-167, 2001.; Abstract (1 page). |
| | AP | Siu, Karen, et al., "An application of phase retrieval x-ray diffractometry to refraction/small-angle scattering data," <i>J. Phys. D: Appl. Phys.</i> , 34: 2912-2917, 2001. |

EXAMINER *Courtney Thomas*DATE CONSIDERED
05.28.07

* EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).